INVESTIGATION OF WORK FUNCTION OF DIFFERENT MATERIALS USING A SYNCHROTRON BEAMLINE

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Photoelectron spectroscopy in VUV range and soft X-ray radiation may be used in investigating electron structure of different materials [1,2]. In addition one can infer about material structure and about the electron work function [3].

During the meeting we want to discuss the possibility of building an experimental station including a vacuum monochromator and a suitable system for electron detection. Discussing a mounting system of various samples and data acquisition possibilities is of great importance. Our group is interested in participating in building of the station and its usage.

References:

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